

U.S. Patent Documents

| Examiner<br>Initials | Document<br>No. | Date | Name          | Class Subclass | Filing Date<br>If Approp. |
|----------------------|-----------------|------|---------------|----------------|---------------------------|
| <i>pt</i>            | 09/793,624      | 2/01 | Edamura       |                |                           |
| <i>pt</i>            | 09/797,601      | 3/01 | Usui          |                |                           |
| <i>pt</i>            | 6,261,470       | 7/01 | Smith et al   |                |                           |
| <i>pt</i>            | 2001/0016053    | 8/01 | Dickson et al |                |                           |
| <i>pt</i>            | 09/946,504      | 9/01 | Usui et al    |                |                           |

Foreign Patent Documents

| Document<br>No.          | Date  | Country  | Class Subclass | Translation<br>Yes No |
|--------------------------|-------|----------|----------------|-----------------------|
| <i>pt</i> — 2000-228397  | 8/00  | Japan    |                |                       |
| <i>pt</i> — 2000-324297  | 11/00 | Japan    |                |                       |
| <i>pt</i> — EP 1 089 146 | 4/01  | European |                |                       |

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

- pt* — CRC Handbook of Chemistry and Physics, D. Lide, CRC Pres, R.W.B. Pearse & A. G. Gaydon, "the Identification of Molecular Spectra", J. Wiley & Sons, Inc., 1976
- pt* — S. Minami: "Waveform Data Processing for Scientific Measurements", CQ Publication Co. of Japan, pp. 220-226 (1986)
- pt* — K. Sasaki, et al, "Estimation of Component Spectral Curves from Unknown Mixture Spectra", Appl. Opt., Vol. 23, pp. 1955-1959 (1984)

Examiner *P. Hassanzadeh*

Date Considered *5-20-04*

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.